

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/709,823	CHANG CHIEN ET AL.	
Examiner		Art Unit		Page 1 of 1
Tanh Q. Nguyen		2182		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,438,604 B1	08-2002	Kuver et al.	709/234
*	B	US-5,220,211 A	06-1993	Christopher et al.	326/90
*	C	US-6,907,490 B2	06-2005	Kosaraju, Chakravarthy	710/307
*	D	US-2002/0161942 A1	10-2002	Morinaga, Takeo	710/22
*	E	US-5,968,167 A	10-1999	Whittaker et al.	712/225
*	F	US-6,941,060 B1	09-2005	Nagaishi et al.	386/52
*	G	US-6,643,728 B1	11-2003	Crutchfield et al.	710/315
*	H	US-2003/0169772 A1	09-2003	Bardini et al.	370/503
*	I	US-2004/0128671 A1	07-2004	Koller et al.	718/100
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.